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_	Application/Control No.	Applicant(s)/Patent und Reexamination	er
	10/029,300	IWASAKI, TAKAO	
	Examiner	Art Unit	
	Jacob P. Rohwer	2624	

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SEARCHED			
Class	Subclass	Date	Examiner
358	1.13	6/27/2005	JPR
382	232	6/27/2005	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
·	DATE	EXMR	
East Class 358 (text search only)	6/28/2005	JPR	
East Class 382 (text search only	6/30/2005	JPR	
East Class 358 (Updated text search)	11/17/2005	JPR	